

Vishay Siliconix

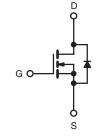
RoHS

COMPLIANT

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	200				
R _{DS(on)} (Ω)	V _{GS} = 10 V	0.18			
Q _g (Max.) (nC)	70				
Q _{gs} (nC)	13				
Q _{gd} (nC)	39				
Configuration	Single				





N-Channel MOSFET

FEATURES

- · Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- · Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION	
Package	TO-220
	IRF640PbF
Lead (Pb)-free	SiHF640-E3
SnPb	IRF640
	SiHF640

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, unless otherw	ise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V _{DS}	200	v	
Gate-Source Voltage		V _{GS}	± 20	v	
Continuous Drain Current	V_{GS} at 10 V $T_C = 25 \degree C$	1-	18		
	$T_{\rm C} = 100 ^{\circ}{\rm C}$	I _D	11	А	
Pulsed Drain Current ^a	I _{DM}	72			
Linear Derating Factor			1.0	W/°C	
Single Pulse Avalanche Energy ^b		E _{AS}	580	mJ	
Repetitive Avalanche Current ^a		I _{AR}	18	А	
Repetitive Avalanche Energy ^a		E _{AR}	13	mJ	
Maximum Power Dissipation	T _C = 25 °C	PD	125	W	
Peak Diode Recovery dV/dt ^c		dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150		
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	°C	
Mounting Torque	C 00 or M0 oprovi		10	lbf ⋅ in	
	6-32 or M3 screw		1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. V_{DD} = 50 V, starting T_J = 25 °C, L = 2.7 mH, R_G = 25 Ω , I_{AS} = 18 A (see fig. 12).

c. $I_{SD} \le 18$ A, dI/dt ≤ 150 A/µs, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RAT	TINGS							
PARAMETER	SYMBOL	TYP.		MAX.		UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-		62				
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50				°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	- 1.0			1		
	•	÷	•					
SPECIFICATIONS $T_J = 25 \ ^{\circ}C$,	unless otherw	vise noted						
PARAMETER	SYMBOL	TEST C	CONDITI	ONS	MIN.	TYP.	MAX.	UNIT
Static								
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0	V, I _D = 2	50 µA	200	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to	o 25 °C, I	l _D = 1 mA	-	0.29	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA		2.0	-	4.0	V	
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA	
Zava Cata Valtaga Drain Current		V _{DS} = 20	0 V, V _{GS}	= 0 V	-	-	25	<u> </u>
Zero Gate Voltage Drain Current	I _{DSS}	$V_{DS} = 160 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 ^{\circ}\text{C}$		-	-	250	μΑ	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	١ _c	₀ = 11 A ^b	-	-	0.18	Ω
Forward Transconductance	g fs	V _{DS} = 50) V, I _D =	11 A ^b	6.7	-	-	S
Dynamic						•	•	
Input Capacitance	C _{iss}	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$		-	1300	-	pF	
Output Capacitance	C _{oss}			-	430	-		
Reverse Transfer Capacitance	C _{rss}	f = 1.0 N	f = 1.0 MHz, see fig. 5		-	130	-	1
Total Gate Charge	Qg				-	-	70	nC
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	l _D = 18 . see fi	A, V _{DS} =160 V, ig. 6 and 13 ^b	-	-	13	
Gate-Drain Charge	Q _{gd}		0001	ig. o and to	-	-	39	
Turn-On Delay Time	t _{d(on)}				-	14	-	
Rise Time	t _r	V_{DD} = 100 V, I _D = 18 A, R _G = 9.1 Ω , R _D = 5.4 Ω , see fig. 10 ^b		-	51	-	ns	
Turn-Off Delay Time	t _{d(off)}			-	45	-		
Fall Time	t _f			-	36	-		
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	- nH	
Internal Source Inductance	Ls			-	7.5	-		
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	18	A	
Pulsed Diode Forward Current ^a	I _{SM}			-	-	72		
Body Diode Voltage	V_{SD}	$T_J = 25 \ ^{\circ}C, I_S = 18 \ A, V_{GS} = 0 \ V^b$		-	-	2.0	V	
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 18 A, dl/dt = 100 A/µs ^b		-	300	610	ns	
Body Diode Reverse Recovery Charge	Q _{rr}			-	3.4	7.1	μC	
Forward Turn-On Time	t _{on}	Intrinsic turn-	on time i	s negligible (turn	on is dor	ninated b	y L _S and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.



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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

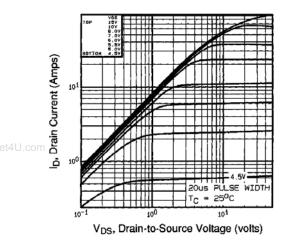


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

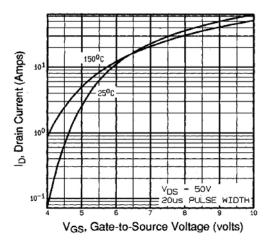


Fig. 3 - Typical Transfer Characteristics

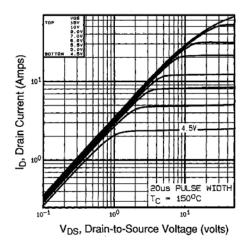


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

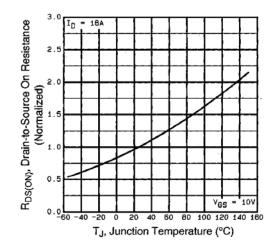


Fig. 4 - Normalized On-Resistance vs. Temperature

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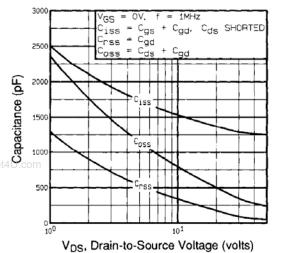


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

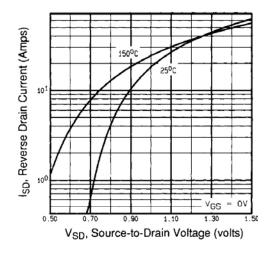


Fig. 7 - Typical Source-Drain Diode Forward Voltage

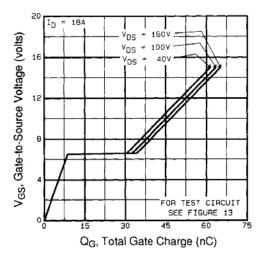


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

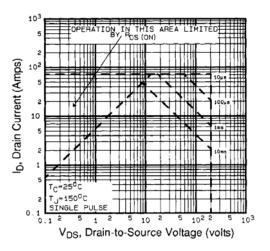


Fig. 8 - Maximum Safe Operating Area

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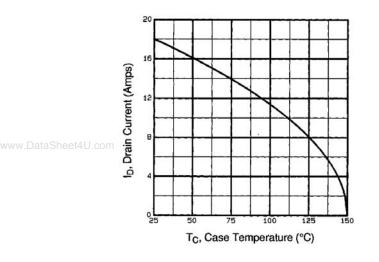


Fig. 9 - Maximum Drain Current vs. Case Temperature

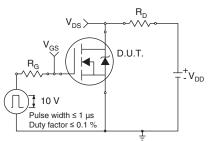


Fig. 10a - Switching Time Test Circuit

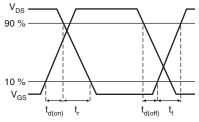


Fig. 10b - Switching Time Waveforms

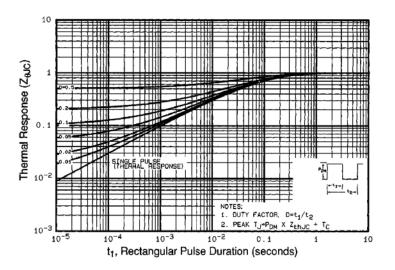


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

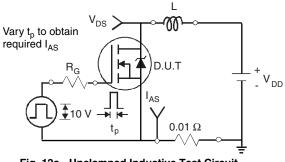


Fig. 12a - Unclamped Inductive Test Circuit

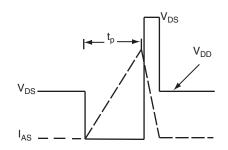
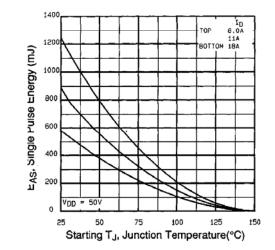


Fig. 12b - Unclamped Inductive Waveforms

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Fig. 12c - Maximum Avalanche Energy vs. Drain Current

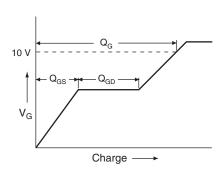


Fig. 13a - Basic Gate Charge Waveform

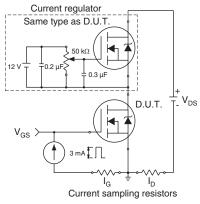
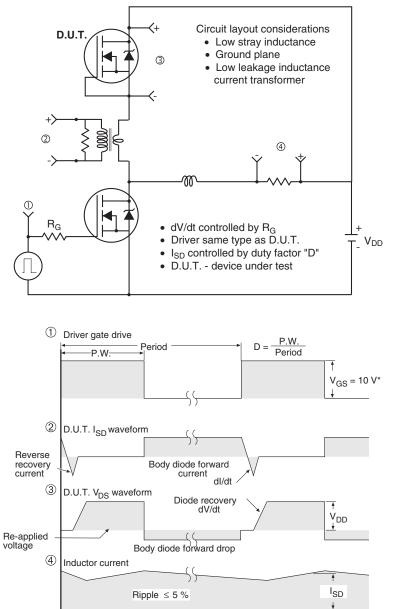


Fig. 13b - Gate Charge Test Circuit

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Peak Diode Recovery dV/dt Test Circuit

* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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